

<b>Notice of References Cited</b>	Application/Control No. 10/002,176	Applicant(s)/Patent Under Reexamination YANG ET AL.	
	Examiner Vikki H Trinh	Art Unit 2814	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

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